

# Daily Program – Day 2

Thursday, August 11

Field A - Grand Ballroom A

- 07:00a Registration Open & Breakfast
- 08:00a Plenary Session: Dr. Mihail Roco
- 08:45a Break and Poster Visitation
- Morning Session 1 - Exposure assessment techniques (1.A)  
Global exposure assessment efforts (1.C) - Chuen-Jinn Tsai
- 09:15a **Four Methods to Implement the Nanotechnology Emission Assessment Technique (NEAT)**  
R. Anderson (*TSI Incorporated, United States*)
- 09:30a **Integration and Gap Analysis of Existing Data for Building Exposure Scenarios for MNMs**  
K. Clark, M. Riediker, The NANEX Consortium, M. van Tongeren (*Institute for Work and Health, Switzerland*)
- 09:45a **A Multi-step Airborne Nanoparticle Assessment Strategy**  
P. O'Shaughnessy, T. Peters, L. Schmoll (*University of Iowa, United States*)
- 10:00a **Time Series Analysis of Nano Exposure Measurements**  
R. Klein Entink, W. Fransman (*TNO Quality of Life, Netherlands*)
- 10:15a **Engineered Nanoparticles: Measurement of Exposure Size Distribution and the Impact on Dose and Health Risk**  
R. Muir, B. Gorbunov, D. Bello (*Nanenum, United Kingdom*)
- 10:30a Break and Poster Visitation
- Morning Session 2 - Good practices and risk management methods (1.F) -  
Jennifer Nash
- 10:45a **Identifying Good Practices in Handling Nanomaterials using the Video Exposure Monitoring Technique Pimex**  
K. Verbist, P. Beurskens, H. Heussen (*Expert Centre for Chemical Risk Management, Netherlands*)
- 11:00a **An Expert Working Group to Promote Nanotechnology Health and Safety**  
M. L. Ostraat, G. Ramachandran, J. D'Arcy, P. O'Shaughnessy, C. Geraci, G. Olson, D. Evans, M. Methner, E. Stevenson, A. Maynard, K. Rickabaugh (*RTI International, United States*)
- 11:15a **The Challenges in Writing Occupational Health and Safety Guidance on Safe Use of Nanomaterials - a UK Perspective**  
J. M. L. Freeland, J. S. Hulme (*University of Strathclyde, United Kingdom*)
- 11:30a **Evaluation of the Safety Measures Against Nanoparticle Release in a Pilot Scale Manufacturing Facility**  
J. Wang, C. Asbach, T. Hülser, H. Fissan, T. Kuhlbusch, D. Y. H. Pui (*Federal Institute of Technology (ETH), Switzerland*)